IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Priority Application Serial No	10/264,615
Priority Filing Date	October 3, 2002
Inventor	Luan C. Tran
Assignee	Micron Technology, Inc.
Priority Group Art Unit	2813
Priority Examiner	Laura M. Schillinger
Attorney's Docket No	MI22-2331
Title: Semiconductor Processing Methods of Forming Integ	rated Circuitry

INFORMATION DISCLOSURE STATEMENT

References - - See attached Form PTO-1449

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. No admission is made regarding whether all the submitted references are prior art.

The listed references were cited by, or submitted to, the Office in the parent, copending application of the above-identified application. The above-identified application is a divisional of co-pending application Serial No. 10/264,615, filed October 3, 2002, upon which the above-identified application relies for a priority date under 35 U.S.C. §120. Such prior disclosure is sufficient for the above-identified application as far as copies of the references are concerned. 37 C.F.R. §1.98(d) and MPEP §609(2). Copies of the foreign references and publications are provided.

Citation of these references is respectfully requested.

Respectfully submitted,

Date: 34/4 //, 2003

Deepak Malhotra Reg. No. 33,560

Wells, St. John, Roberts, Gregory & Matkin P.S.

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Form PTO-1449

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ATTY. DOCKET NO. MI22-2152

SERIAL NO. Unknown

LIST OF ART CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT
Luan C. Tran

(Use several sheets if necessary)					Luan C. Tran								
					FILING DATE Filed herewith		GROUP Filed herewith						
					U.S. PATE	NT DOCUMENTS							
*Examiner Initial		Docur Numb		Date	Name			Class	Subclass		Filing Date If Appropriate		
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	АВ	4,785,	342	11/15/88	YAMANAKA E	ET AL.	-	357	51				
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	AM	EP 0	717 448 A1	06/19/96	EPO							140	
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*Examiner Initial		Document Number	Date	Name		Class	Subclass	Filing Date If Appropriate			
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